KODENSHI

FIXED VOLTAGE REGULATOR (POSITIVE)

KK78LXX

3-TERMINAL 0.1A POSITIVE VOLTAGE REGULATORS

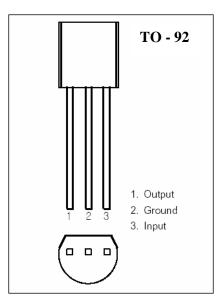
This series of fixed-voltage monolithic integrated-circuit voltage regulators is designed for a wide range of applications.

These applications include on-card regulation for elimination of noise and distribution problems associated with single-point regulation.

In addition, they can be used with power-pass elements to make high current voltage regulators.

Each of these regulators can deliver up to 100mA output current.

The internal limiting and thermal shutdown features of these regulators make them essentially immune to overload. When used as a replacement for a zener diode-resistor combination, an effective improvement in output impedance can be obtained together with lower-bias current.

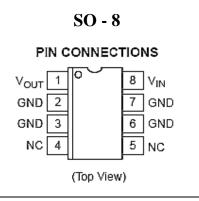


FEATURES

- ♦ Output current Up to 100mA
- \diamond No External Components
- \diamond Internal Thermal Overload Protection
- ♦ Internal Short-Circuit Limiting
- Output Voltage of 5V, 6V, 8V, 9V, 10V, 12V, 15V, 18V and 24V

ABSOLUTE MAXIMUM RATINGS

Cha	racteristic	Symbol	Value	Unit
	IL78L05 ~ IL78L10		30	
Input voltage	IL78L12 ~ IL78L18	VI	35	V
	IL78L24		40	
Operating junction temp	erature	Topr	-40 ~ +150	
Storage temperature		Tstg	-65 ~ +150	°C
Soldering temperature a	ind time	Tsol	260/10sec	

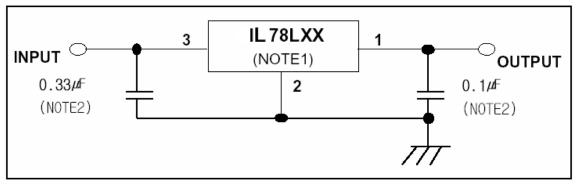




RECOMMENDED OPERATING CONDITIONS

78	Lxx	Min.	Max.	Unit
	IL78L05	7	20	
	IL78L06	8	20	
Input voltage, VI	IL78L08	10.5	23	
	IL78L09	11.5	24	
	IL78L10	12.5	25	V
	IL78L12	14.5	27	
	IL78L15	17.5	30	
	IL78L18	20.5	33	
	IL78L24	26.5	39	
Output current, lo	Output current, lo		100	mA
Operating virtual junction ten	nperature, Tj	-40	125	C

TYPICAL APPLICATION



Notes

- 1. To specify an output voltage, substitute voltage for "XX"
- 2. Bypass capacitors are recommended for optimum stability and transient response and should be located as close as possible to the regulators.

IL78L05 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=10V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test cond	ition *	Min	Тур.	Max.	Unit
		25°C		4.8	5	5.2	
Output voltage **	Vout	$1_{mA} \le Io \le 40_{mA}$ $7V \le VI \le Vmax$	-40 ~ 125℃	4.75	5	5.25	V
		1mA≤lo≤ 70mA	-	4.75	5	5.25	
Line regulation	Reg line	7≤ VI≤ 20V	25°C		32	150	-2/
	Regime	8≤ VI≤ 20V	230		26	100	mV
Load regulation	Reg load	1 mA \leq lo \leq 100mA	− 25°C		15	60	mV
Load regulation	rtog lodd	1 mA \leq lo \leq 40mA	200		8	30	
Bias current	I _B		25℃		3.8	6	
Dias current	чВ		125℃			5.5	mA
Bias current change	∆l _B	9≤ VI≤ 20V	-40 ~ 125℃			1.5	٨
bias current change	ΔIB	1 mA \leq lo \leq 40mA	-40 ~ 123 (0.1	mA
Output noise voltage	V _N	10 Hz $\leq f \leq 100$ kHz	25 ℃		42		μN
Ripple rejection	RR	$8 \le VI \le 20V$ f=120Hz	25°C	41	49		dB
Dropout voltage	V _D		25 ℃		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33μ F capacitor across the input and a 0.1μ F capacitor across the output.

IL78L18 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=23V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test cond	ition *	Min	Тур.	Max.	Unit
			25°C	17.3	18	18.7	
Output voltage **	Vout	$1_{mA} \le lo \le 40_{mA}$ $20.5V \le VI \le 33V$	-40 ~ 125℃	17.1	18	18.9	V
		1mA≤lo≤ 70mA		17.1	18	18.9	
Line regulation	Poglipo	20.5≤ VI≤ 33V	25 °C		70	360	-24
	Reg line	22≤ VI≤ 33V	25℃ –		64	300	mV
	Reg load	1 mA \leq lo \leq 100mA	- 25℃ -		27	180	mV
Load regulation	Regioad	1 mA \le lo \le 40mA			19	90	
Bias current			25°C		4.7	6.5	
bias current	Ι _Β		125℃			6	mA
Bias current change	<u>^ </u>	22≤ VI≤ 33V	-40 ~ 125℃			1.5	
bias current change	∟I _B	1 mA \leq lo \leq 40mA	40 ~ 125 (0.1	mA
Output noise voltage	V _N	$10H_z \le f \le 100kH_z$	25°C		82		μN
Ripple rejection	RR	$21.5 \le VI \le 31.5V$ f=120Hz	25°C	32	36		dB
Dropout voltage	V _D		25°C		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33μ F capacitor across the input and a 0.1μ F capacitor across the output.

IL78L24 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=26V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test cond	ition *	Min	Тур.	Max.	Unit
			25℃	23	24	25	
Output voltage **	Vout	$1_{mA} \le I_0 \le 40_{mA}$ $26.5V \le VI \le 39V$	-40 ~ 125 <i>°</i> C	22.8	24	25.2	V
		1mA≤lo≤ 70mA		22.8	24	25.2	
Line regulation	Reg line	26.5≤ VI≤ 39V	25℃		95	480	-24
	Regime	29≤ VI≤ 39V	250		78	400	mV
	Reg load	1 mA \leq lo \leq 100mA	25℃		41	240	mV
Load regulation	Regioad	1 mA \leq lo \leq 40mA	200		28	120	
Bias current	I _B		25℃		4.8	6.5	٨
bias current			125℃			6	mA
Bias current change	∆l _B	28≤ VI≤ 39V	-40 ~ 125℃			1.5	٨
bias current change	ΔIB	1 mA \leq lo \leq 40mA	-40 ~ 125 C			0.1	mA
Output noise voltage	V _N	$10H_z \leq f \leq 100$ kHz	25℃		82		μN
Ripple rejection	RR	$27.5 \le VI \le 37.5V$ f=120Hz	25°C	30	33		dB
Dropout voltage	V _D		25 ℃		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33μ F capacitor across the input and a 0.1μ F capacitor across the output.

IL78L09 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=14V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test cond	ition *	Min	Тур.	Max.	Unit
			25 ℃	806	9	9.4	
Output voltage **	Vout	$1_{mA} \le Io \le 40_{mA}$ $12V \le VI \le 24V$	-40 ~ 125℃	8.55	9	9.45	V
		1mA≤lo≤ 70mA		8.55	9	9.45	
Line regulation	Reg line	12≤ VI≤ 24V	25°C		45	175	mV
	Regime	13≤ VI≤ 24V	250		40	125	mv
	Reg load	1 mA \leq lo \leq 100mA	- 25°C		19	90	mV
Load regulation	Regioad	1 mA \leq lo \leq 40mA	250		11	40	
Bias current			25℃		4.1	6	٨
Dias current	Ι _Β		125℃			5.5	mA
Bias current change	<u>^ </u>	13≤ VI≤ 24V	-40 ~ 125℃			1.5	
Blas current change	∟I _B	1 mA \leq lo \leq 40mA	-40 ~ 125 (0.1	mA
Output noise voltage	V _N	$10H_z \le f \le 100kH_z$	25°C		58		μN
Ripple rejection	RR	$13 \le VI \le 23V$ f=120Hz	25°C	38	45		dB
Dropout voltage	V _D		25 ℃		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33μ capacitor across the input and a 0.1μ capacitor across the output.

IL78L10 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=16V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test cond	ition *	Min	Тур.	Max.	Unit
			25℃	9.6	10	10.4	
Output voltage **	Vout	$1_{mA} \le Io \le 40_{mA}$ $13V \le VI \le 25V$	-40 ~ 125℃	9.5	10	10.5	V
		1mA≤lo≤ 70mA		9.5	10	10.5	
Line regulation	Poglipo	13≤ VI≤ 25V	25℃		51	175	-24
	Reg line	14≤ VI≤ 25V	250		42	125	mV
Load regulation	Reg load	1 mA \leq lo \leq 100mA	− 25°C		20	90	mV
Luau regulation	Regioad	1 mA \leq lo \leq 40mA	250		11	40	
Bias current			25°C		4.2	6	
Dias current	Ι _Β		125℃			5.5	mA
Bias current change	<u>^ </u>	14≤ VI≤ 25V	-40 ~ 125℃			1.5	
bias current change	∟I _B	1 mA \leq lo \leq 40mA	-40 ~ 125 C			0.1	mA
Output noise voltage	V _N	$10H_z \le f \le 100kH_z$	25 ℃		62		μN
Ripple rejection	RR	$15 \le VI \le 25V$ f=120Hz	25°C	37	44		dB
Dropout voltage	V _D		25℃		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33μ F capacitor across the input and a 0.1μ F capacitor across the output.

IL78L12 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=17V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test cond	ition *	Min	Тур.	Max.	Unit
			25 °C	11.5	12	12.5	
Output voltage **	Vout	$1_{mA} \le Io \le 40_{mA}$ $14V \le VI \le 27V$	-40 ~ 125 ℃	11.4	12	12.6	V
		1mA≤lo≤ 70mA		11.4	12	12.6	
Line regulation	Reg line	14.5≤ VI≤ 27V	25℃		55	250	
	Regime	16≤ VI≤ 27V	230		49	200	mV
Load regulation	Reg load	1 mA \leq lo \leq 100mA	- 25°C		22	100	mV
Load regulation	Regioud	1 mA \leq lo \leq 40mA	200		13	50	
Bias current	I _B		25℃		4.3	6.5	mA
Dias current	'B		125℃			6	IIIA
Bias current change	⊳I _B	16≤ VI≤ 27V	-40 ~ 125℃			1.5	
Dias current change	ΔB	1 mA \leq lo \leq 40mA	-40 ~ 123 0			0.1	mA
Output noise voltage	V _N	10 Hz $\leq f \leq 100$ kHz	25°C		70		μN
Ripple rejection	RR	$15 \le VI \le 25V$ f=120Hz	25°C	37	42		dB
Dropout voltage	V _D		25 ℃		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33μ F capacitor across the input and a 0.1μ F capacitor across the output.

IL78L15 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=19V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test cond	ition *	Min	Тур.	Max.	Unit
			25℃	14.4	15	15.6	
Output voltage **	Vout	$1_{mA} \le Io \le 40_{mA}$ $17.5V \le VI \le 30V$	-40 ~ 125℃	14.25	15	15.75	V
		1mA≤lo≤ 70mA		14.25	15	15.75	
Line regulation	Reg line	17.5≤ VI≤ 30V	25°C		65	300	
	Regime	19≤ VI≤ 30V	250		58	250	mV
Load regulation	Reg load	1 mA \leq lo \leq 100mA	25℃		25	150	mV
	Regioad	1 mA \leq lo \leq 40mA	200		15	75	
Bias current			25°C		4.2	6.5	
Dias Current	Ι _Β		125℃			6	mA
Bias current change	∆l _B	19≤ VI≤ 30V	-40 ~ 125℃			1.5	
bias current change		1 mA \leq lo \leq 40mA	-40 ~ 125 C			0.1	mA
Output noise voltage	V _N	$10H_z \leq f \leq 100$ kHz	25℃		82		μV
Ripple rejection	RR	$18.5 \le VI \le 28.5V$ f=120Hz	25°C	37	44		dB
Dropout voltage	V _D		25 ℃		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33μ F capacitor across the input and a 0.1μ F capacitor across the output.

IL78L18 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=23V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test cond	ition *	Min	Тур.	Max.	Unit
			25 ℃	17.3	18	18.7	
Output voltage **	Vout	$1_{mA} \le lo \le 40_{mA}$ $20.5V \le VI \le 33V$	-40 ~ 125℃	17.1	18	18.9	V
		1mA≤lo≤ 70mA		17.1	18	18.9	
Line regulation	Reg line	20.5≤ VI≤ 33V	− 25°C		70	360	
	Regime	22≤ VI≤ 33V	230		64	300	mV
Load regulation	Reg load	1 mA \leq lo \leq 100mA	- 25°C		27	180	mV
Luau regulation	ntog lodd	1 mA \leq lo \leq 40mA	230		19	90	
Bias current	I _B		25℃		4.7	6.5	mA
Dias current	'B		125℃			6	IIIA
Bias current change	⊳I _B	$22 \le VI \le 33V$	-40 ~ 125℃			1.5	
Dias current change	ΔB	1 mA \leq lo \leq 40mA	-40 ~ 123 0			0.1	mA
Output noise voltage	V _N	$10H_z \le f \le 100$ kHz	25 ℃		82		μN
Ripple rejection	RR	$21.5 \le VI \le 31.5V$ f=120Hz	25°C	32	36		dB
Dropout voltage	V _D		25°C		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33μ F capacitor across the input and a 0.1μ F capacitor across the output.

IL78L24 ELECTRICAL CHARACTERISTICS

(At specified virtual junction temperature, VI=26V, Io=40mA (unless otherwise noted)

Characteistic	Symbol	Test cond	ition *	Min	Тур.	Max.	Unit
			25 ℃	23	24	25	
Output voltage **	Vout	$1_{mA} \le Io \le 40_{mA}$ $26.5V \le VI \le 39V$	-40 ~ 125℃	22.8	24	25.2	V
		1mA≤lo≤ 70mA		22.8	24	25.2	
Line regulation	Poglipo	26.5≤ VI≤ 39V	- 25°C		95	480	-24
	Reg line	29≤ VI≤ 39V	250		78	400	mV
	Reg load	1 mA \leq lo \leq 100mA	- 25°C		41	240	- W
Load regulation	Regioad	1 mA \leq lo \leq 40mA	200		28	120	
Bias current			25°C		4.8	6.5	
bias current	Ι _Β		125℃			6	mA
Bias current change	∆l _B	28≤ VI≤ 39V	-40 ~ 125℃			1.5	٨
bias current change	ΔIB	1 mA \leq lo \leq 40 mA	40 ~ 123 0			0.1	mA
Output noise voltage	V _N	$10H_z \le f \le 100kH_z$	25°C		82		μN
Ripple rejection	RR	$27.5 \le VI \le 37.5V$ f=120Hz	25°C	30	33		dB
Dropout voltage	V _D		25 ℃		1.7		V

Notes

*. Pulse testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible.

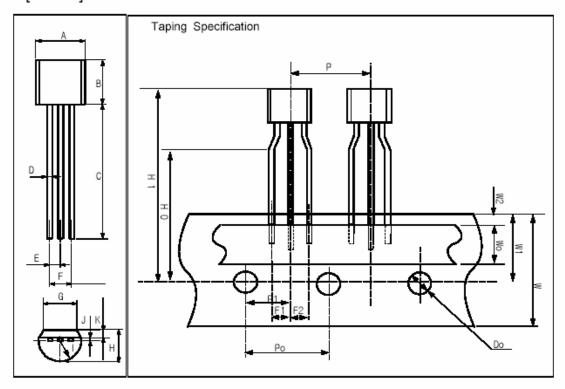
Thermal effects must be taken into account separately.

All characteristics are measured with a 0.33μ F capacitor across the input and a 0.1μ F capacitor across the output.



PACKAGE OUTLINE

[TO-92]

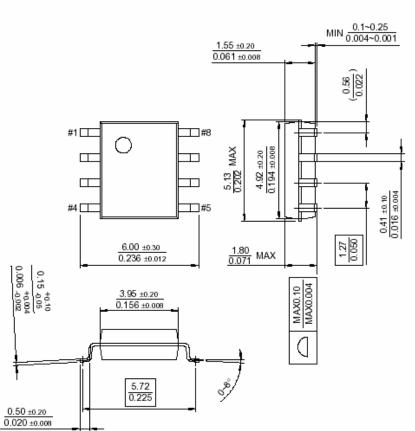


	Package Dime	nsion(unit:mm)			Taping Dimen	sion(unit:mm)	
Symbol	Min	Тур	Max	Symbol	Min	Тур	Max
A	4.43	4.58	4.83	Р	12.2	12.7	13.2
В	4.38	4.58	4.78	PO	12.5	12.7	12.9
с	14.07	14.47	14.87	P1	5.85	6.35	6.85
D	0.36	0.46	0.56	F1,F2	2.4	2.5	2.9
E	1.07	1.27	1.47	w	17.5	18.0	19.0
F	2.34	2.54	2.74	wo	5.5	6.0	6.5
G	3.40	3.60	3.80	W1	8.5	9.0	9.5
н	-	-	3.86	W2	-	-	1.0
I	-	[R2.29]	-	но	15.5	16.0	16.5
J	0.33	0.38	0.39	H1	-	-	27.0
к	0.92	1.02	1.12	DO	3.8	4.0	4.2



Mechanical Dimensions (Continued)

Package



8-SOP